

Complementary N- and P-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY

	V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ)
N-Channel	40	0.030 at V _{GS} = 10 V	8	9.6
		0.034 at V _{GS} = 4.5 V	8	
P-Channel	- 40	0.032 at V _{GS} = - 10 V	- 8	21
		0.041 at V _{GS} = - 4.5 V	- 8	

FEATURES

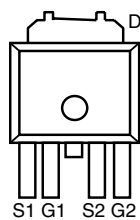
- TrenchFET[®] Power MOSFET
- 100 % R_g and UIS Tested

APPLICATIONS

- CCFL Inverter
- LCD TV and Monitor

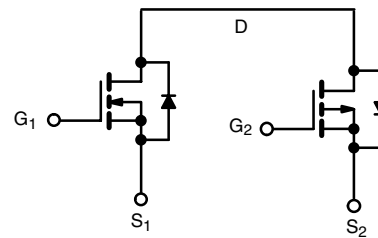


TO-252-4L
D-PAK



Top View
Drain Connected to
Tab

Ordering Information: SUD50NP04-62-T4-E3 (Lead (Pb)-free)



N-Channel MOSFET P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter		Symbol	N-Channel	P-Channel	Unit
Drain-Source Voltage		V _{DS}	40	- 40	V
Gate-Source Voltage		V _{GS}	± 16		
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	I _D	8	- 8	A
	T _C = 70 °C		8	- 8	
	T _A = 25 °C		8 ^{b, c}	- 8 ^{b, c}	
	T _A = 70 °C		8 ^{b, c}	- 8 ^{b, c}	
Pulsed Drain Current (10 μs Pulse Width)		I _{DM}	35	- 35	
Source-Drain Current Diode Current	T _C = 25 °C	I _S	8	- 8	
	T _A = 25 °C		5 ^{b, c}	- 5.5 ^{b, c}	
Pulsed Source-Drain Current		I _{SM}	35	- 35	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	10	20	mJ
Single Pulse Avalanche Energy		E _{AS}	5	20	
Maximum Power Dissipation	T _C = 25 °C	P _D	15.6	23.5	W
	T _C = 70 °C		10	15	
	T _A = 25 °C		6 ^{b, c}	6.7 ^{b, c}	
	T _A = 70 °C		3.9 ^{b, c}	4.3 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	N-Channel		P-Channel		Unit
		Typ	Max	Typ	Max	
Maximum Junction-to-Ambient ^{b, d}	R _{thJA}	17	20.5	15.2	18.5	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	6.6	8	4.4	5.3	

Notes:

a. Based on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 Board.

c. t = 10 sec.

d. Maximum under Steady State conditions is 53 °C/W (N-Channel) and 50 °C/W (P-Channel).

SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions		Min	Typ ^a	Max	Unit
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	N-Ch	40			V
		V _{GS} = 0 V, I _D = - 250 μA	P-Ch	- 40			
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = 250 μA	N-Ch		37		
		I _D = - 250 μA	P-Ch		- 38		
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J	I _D = 250 μA	N-Ch		- 5		
		I _D = - 250 μA	P-Ch		4.0		
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	N-Ch	0.6		2.0	
		V _{DS} = V _{GS} , I _D = - 250 μA	P-Ch	- 0.8		- 2.2	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 16 V	N-Ch			100	nA
			P-Ch			- 100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V	N-Ch			1	μA
		V _{DS} = - 40 V, V _{GS} = 0 V	P-Ch			- 1	
		V _{DS} = 40 V, V _{GS} = 0 V, T _J = 55 °C	N-Ch			10	
		V _{DS} = - 40 V, V _{GS} = 0 V, T _J = 55 °C	P-Ch			- 10	
On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	N-Ch	20			A
		V _{DS} = - 5 V, V _{GS} = - 10 V	P-Ch	- 20			
Drain-Source On-State Resistance ^b	r _{DS(on)}	V _{GS} = 10 V, I _D = 6 A	N-Ch		0.025	0.030	Ω
		V _{GS} = - 10 V, I _D = - 6 A	P-Ch		0.026	0.032	
		V _{GS} = 4.5 V, I _D = 4.8 A	N-Ch		0.028	0.034	
		V _{GS} = - 4.5 V, I _D = - 4.9 A	P-Ch		0.034	0.041	
Forward Transconductance ^b	g _{fs}	V _{DS} = 15 V, I _D = 6 A	N-Ch		20		S
		V _{DS} = - 15 V, I _D = - 6 A	P-Ch		17		
Dynamic ^a							
Input Capacitance	C _{iss}	N-Channel V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz	N-Ch		855		pF
			P-Ch		1505		
Output Capacitance	C _{oss}	P-Channel V _{DS} = - 20 V, V _{GS} = 0 V, f = 1 MHz	N-Ch		105		
			P-Ch		230		
Reverse Transfer Capacitance	C _{rss}		N-Ch		65		
			P-Ch		175		
Total Gate Charge	Q _g	V _{DS} = 20 V, V _{GS} = 10 V, I _D = 5 A	N-Ch		21	32	nC
		V _{DS} = - 20 V, V _{GS} = - 10 V, I _D = - 5 A	P-Ch		41	62	
		N-Channel V _{DS} = 20 V, V _{GS} = 4.5 V, I _D = 5 A	N-Ch		9.6	14.5	
			P-Ch		21	31	
Gate-Source Charge	Q _{gs}	P-Channel V _{DS} = - 20 V, V _{GS} = - 4.5 V, I _D = - 5 A	N-Ch		2.3		
			P-Ch		4.5		
Gate-Drain Charge	Q _{gd}		N-Ch		3.2		
			P-Ch		9.2		
Gate Resistance	R _g	f = 1 MHz	N-Ch		2.5	3.8	Ω
			P-Ch		6.5	10	



SPECIFICATIONS $T_J = 25\text{ }^{\circ}\text{C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions		Min	Typ ^a	Max	Unit
Dynamic ^a							
Turn-On Delay Time	$t_{d(on)}$	N-Channel $V_{DD} = 20\text{ V}$, $R_L = 4\text{ }\Omega$ $I_D \cong 5\text{ A}$, $V_{GEN} = 10\text{ V}$, $R_g = 1\text{ }\Omega$	N-Ch		6	12	ns
			P-Ch		7	14	
Rise Time	t_r		N-Ch		21	32	
			P-Ch		23	35	
Turn-Off Delay Time	$t_{d(off)}$	N-Ch		24	36		
		P-Ch		51	77		
Fall Time	t_f	N-Ch		9	15		
		P-Ch		50	80		
Turn-On Delay Time	$t_{d(on)}$	N-Channel $V_{DD} = 20\text{ V}$, $R_L = 4\text{ }\Omega$ $I_D \cong 5\text{ A}$, $V_{GEN} = 4.5\text{ V}$, $R_g = 1\text{ }\Omega$	N-Ch		12	20	
			P-Ch		40	60	
Rise Time	t_r		N-Ch		75	115	
			P-Ch		106	160	
Turn-Off Delay Time	$t_{d(off)}$	P-Channel $V_{DD} = -20\text{ V}$, $R_L = 4\text{ }\Omega$ $I_D \cong -5\text{ A}$, $V_{GEN} = -10\text{ V}$, $R_g = 1\text{ }\Omega$	N-Ch		40	60	
			P-Ch		45	70	
Fall Time	t_f		N-Ch		56	85	
			P-Ch		50	75	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^{\circ}\text{C}$	N-Ch			8	A
			P-Ch			- 8	
Pulse Diode Forward Current ^a	I_{SM}		N-Ch			35	A
			P-Ch			- 35	
Body Diode Voltage	V_{SD}	$I_S = 1.5\text{ A}$	N-Ch		0.73	1.2	V
		$I_S = -1.6\text{ A}$	P-Ch		- 0.73	- 1.2	
Body Diode Reverse Recovery Time	t_{rr}	N-Channel $I_F = 5\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^{\circ}\text{C}$	N-Ch		26	40	ns
			P-Ch		30	45	
Body Diode Reverse Recovery Charge	Q_{rr}		N-Ch		21	32	nC
			P-Ch		24	36	
Reverse Recovery Fall Time	t_a	P-Channel $I_F = -5\text{ A}$, $di/dt = -100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^{\circ}\text{C}$	N-Ch		13		ns
			P-Ch		15		
Reverse Recovery Rise Time	t_b		N-Ch		13		
			P-Ch		15		

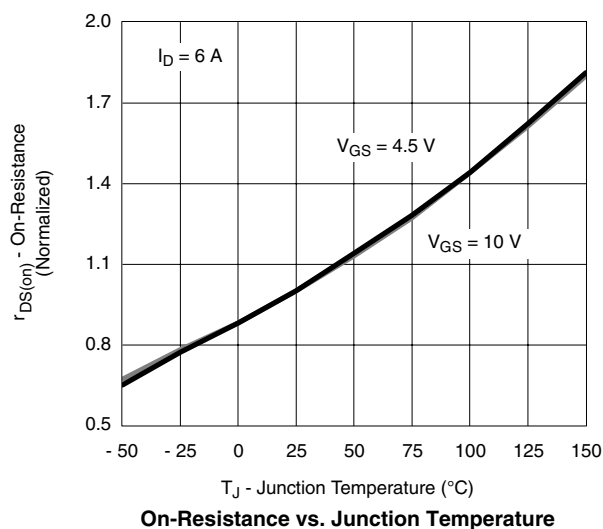
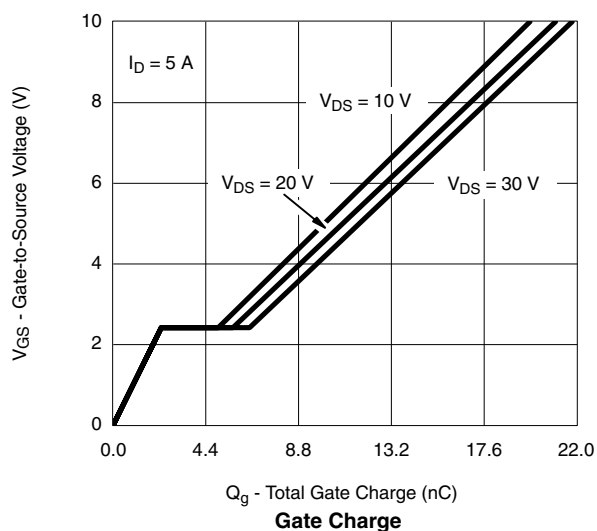
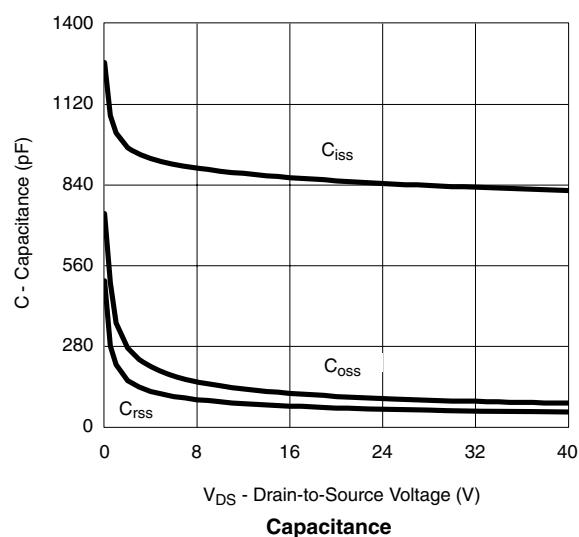
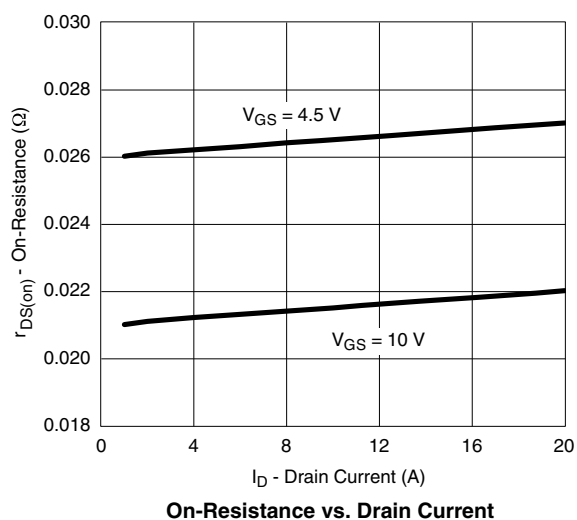
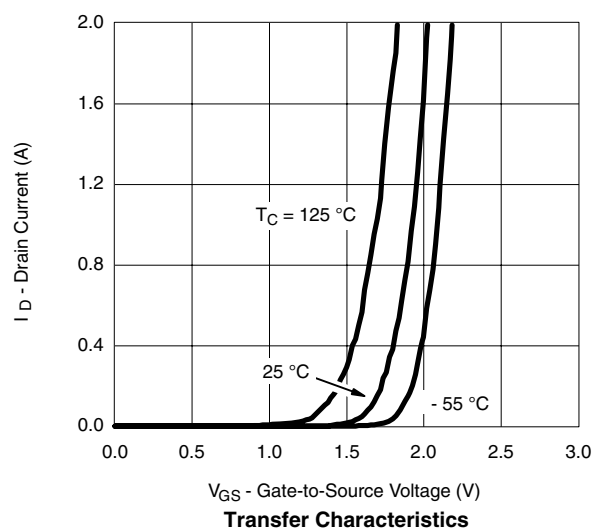
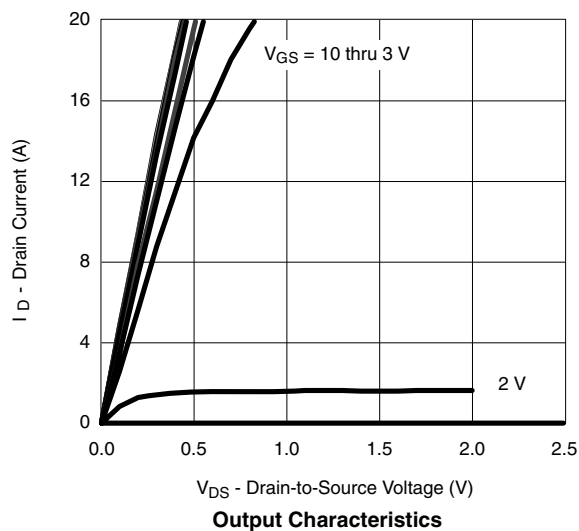
Notes:

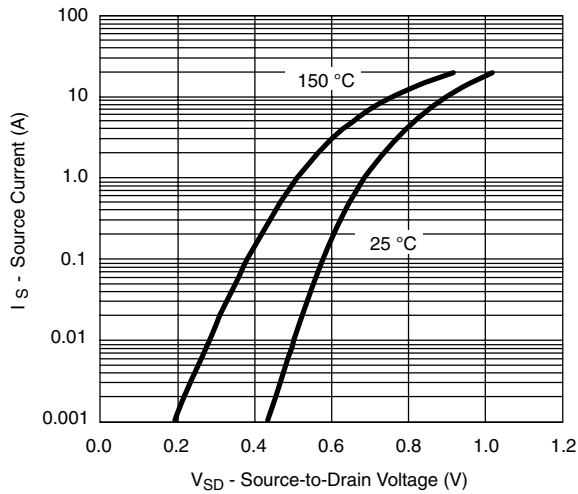
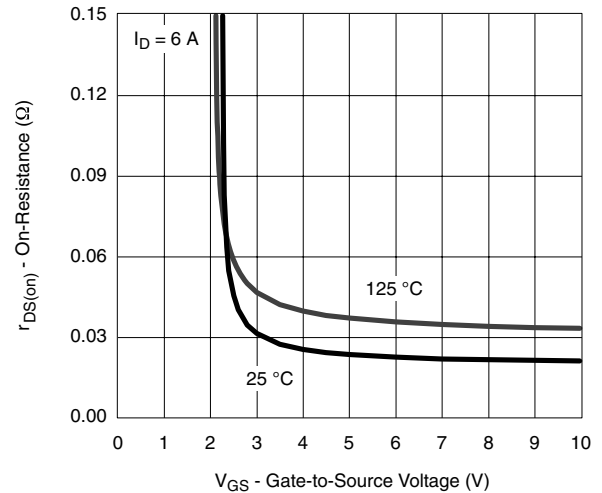
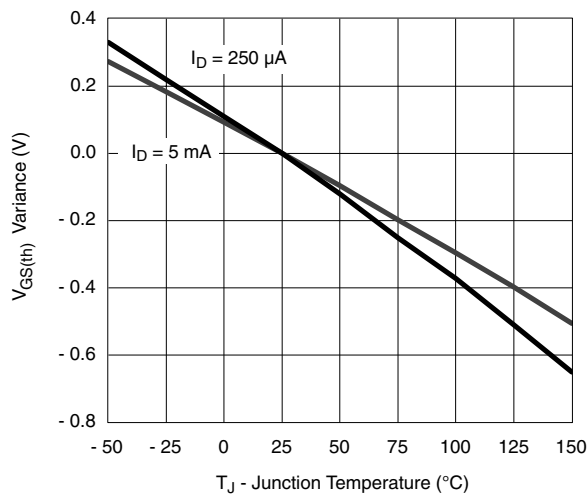
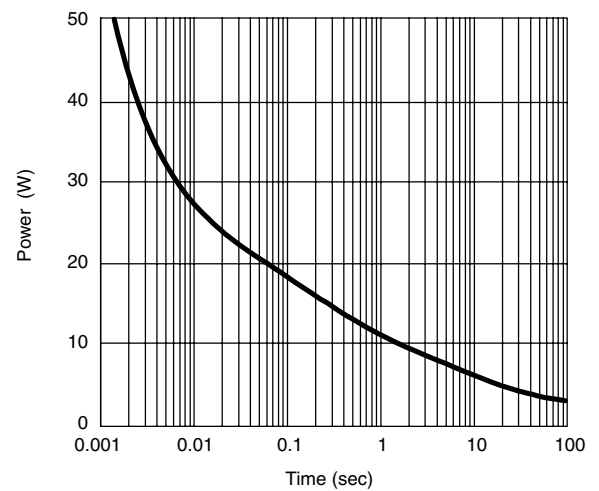
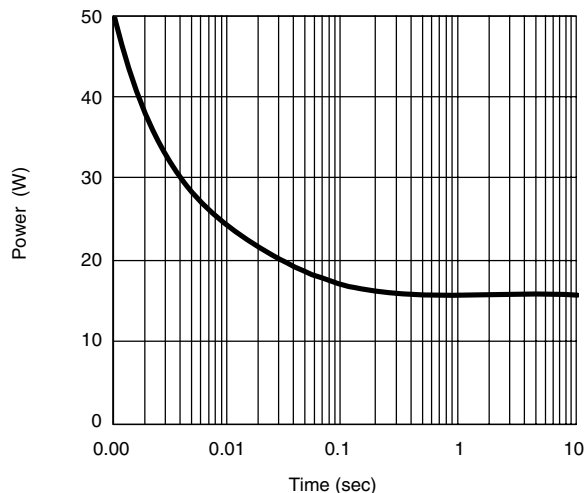
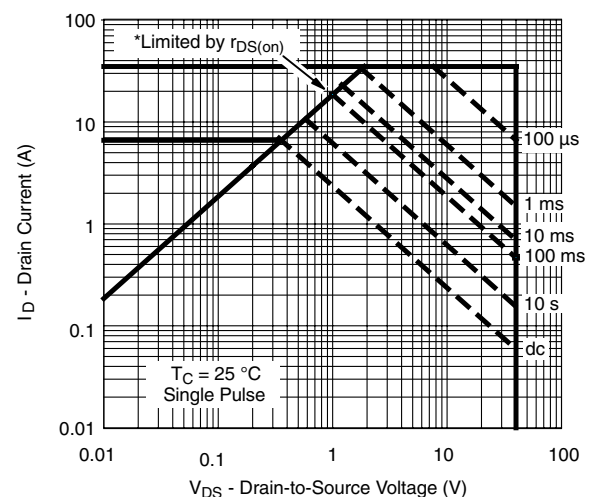
a. Guaranteed by design, not subject to production testing.

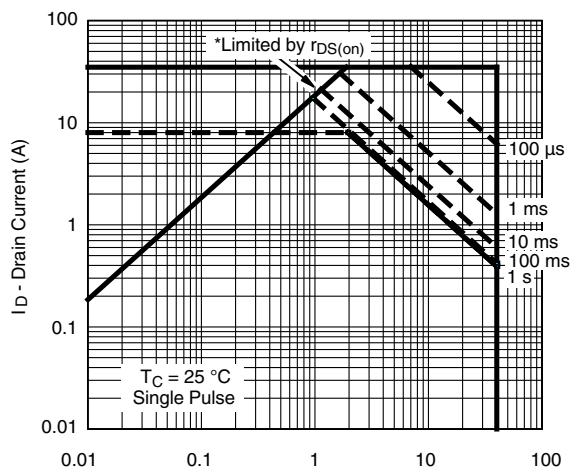
b. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

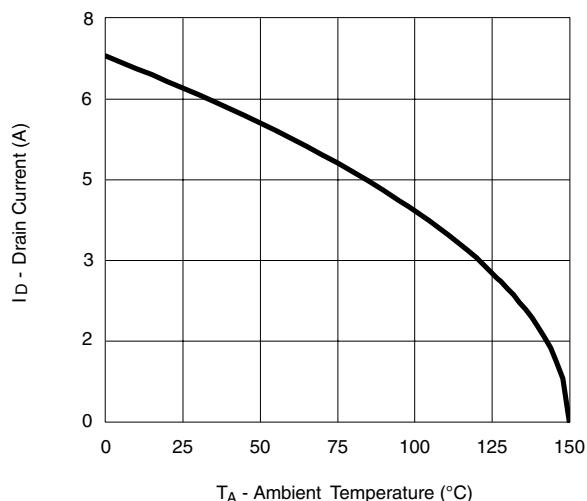
N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless noted



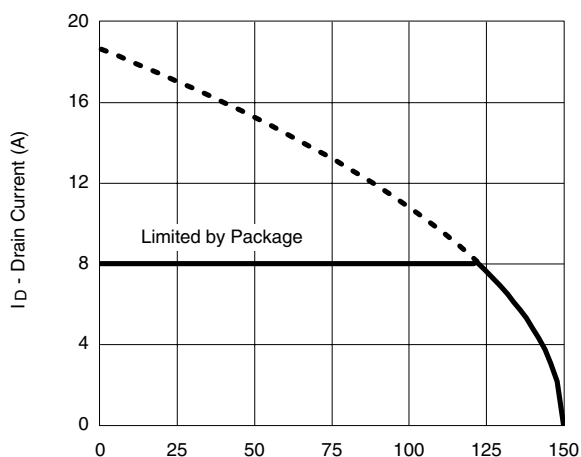
**N-CHANNEL TYPICAL CHARACTERISTICS** 25 °C, unless noted**Source-Drain Diode Forward Voltage****On-Resistance vs. Gate-to-Source Voltage****Threshold Voltage****Single Pulse Power, Junction-to-Ambient****Single Pulse Power, Junction-to-Case*** V_{GS} > minimum V_{GS} at which $r_{DS(on)}$ is specified**Safe Operating Area, Junction-to-Ambient**

N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless noted

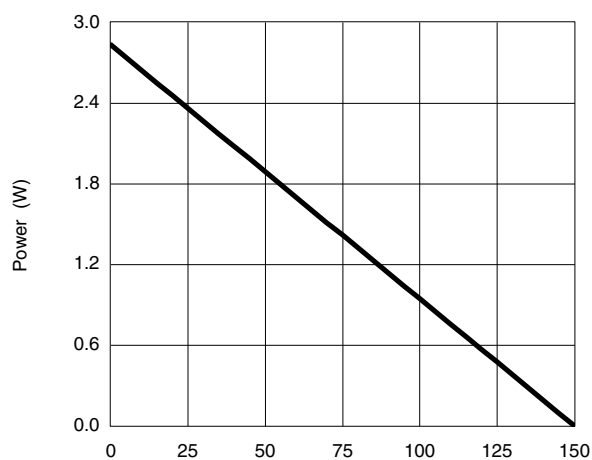
* $V_{GS} >$ minimum V_{GS} at which $r_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Case



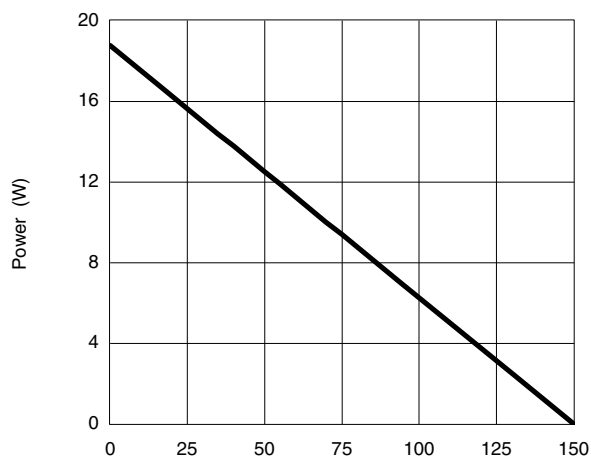
Current Derating, Junction-to-Ambient



Current Derating, Junction-to-Case

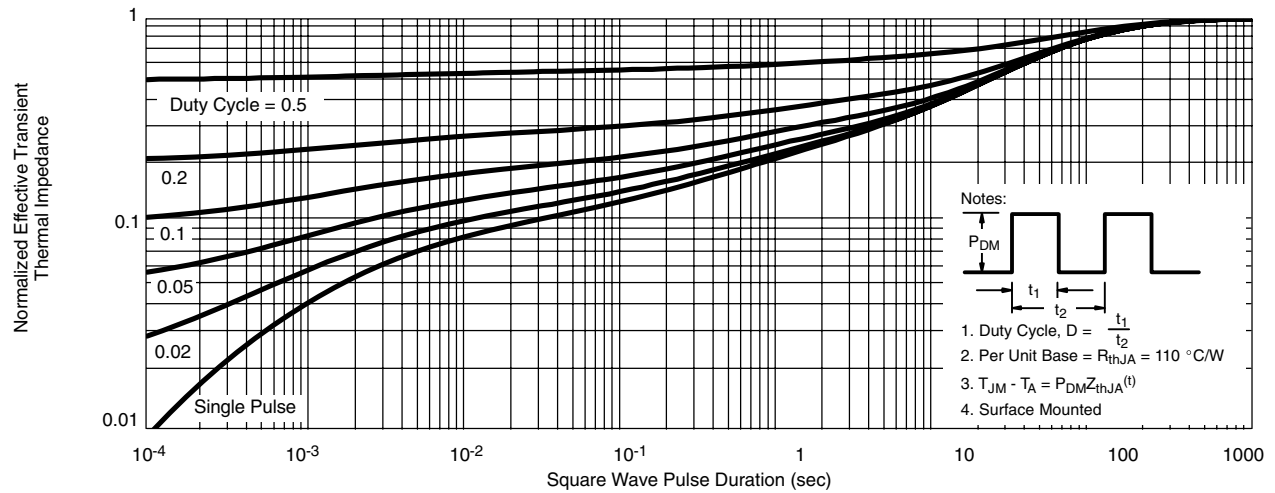


Power Derating, Junction-to-Ambient

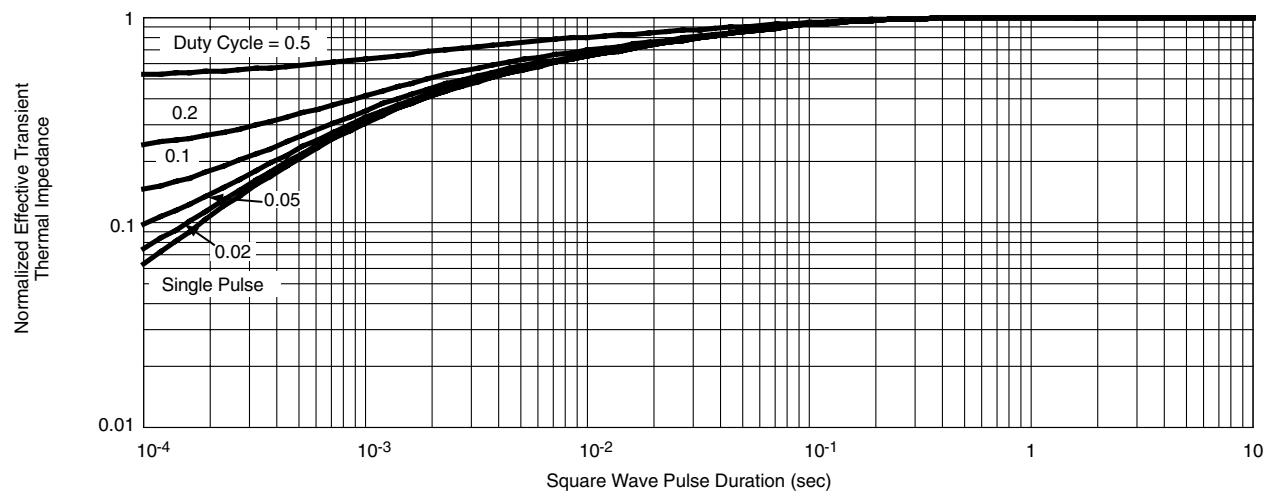


Power Derating, Junction-to-Case

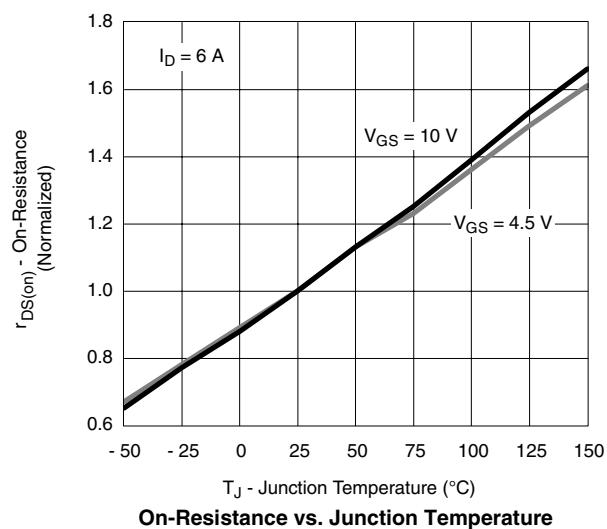
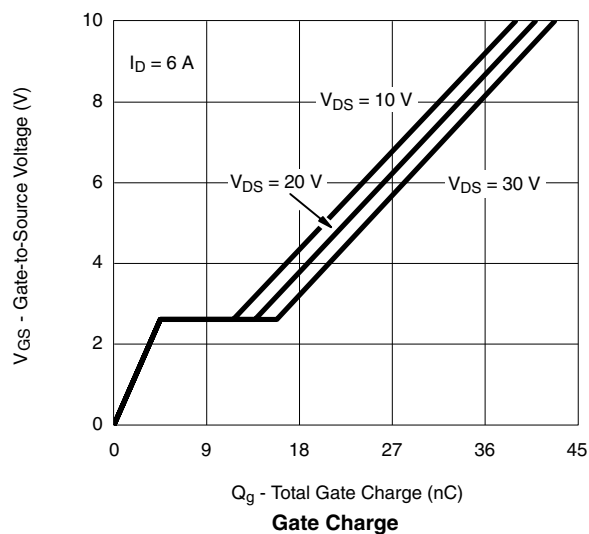
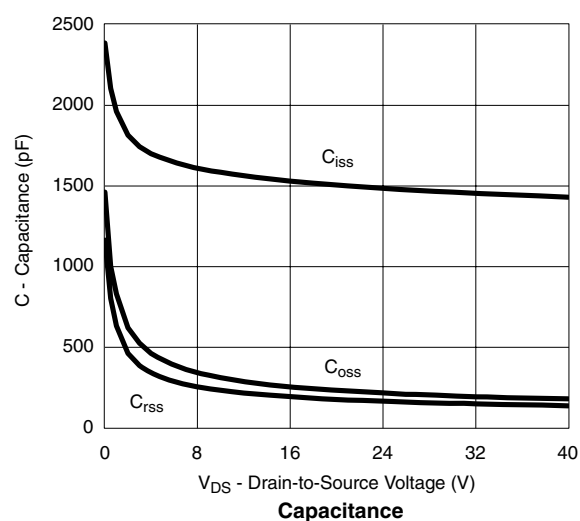
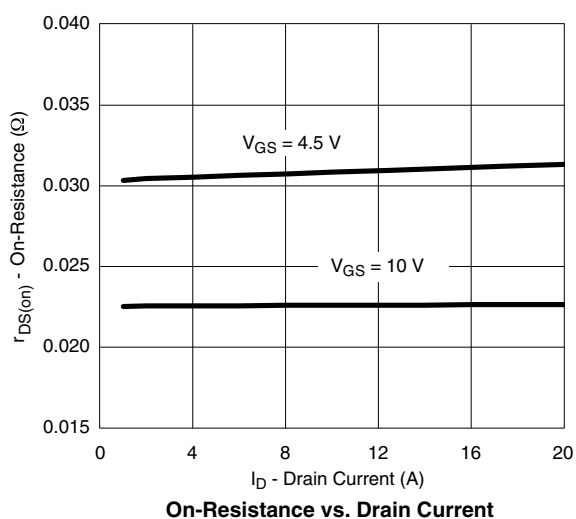
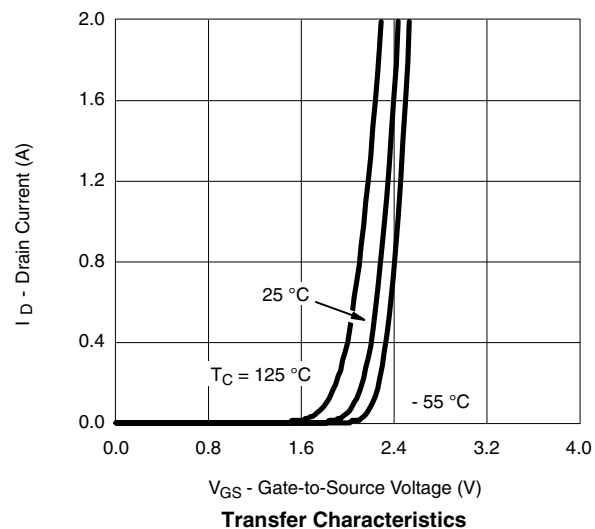
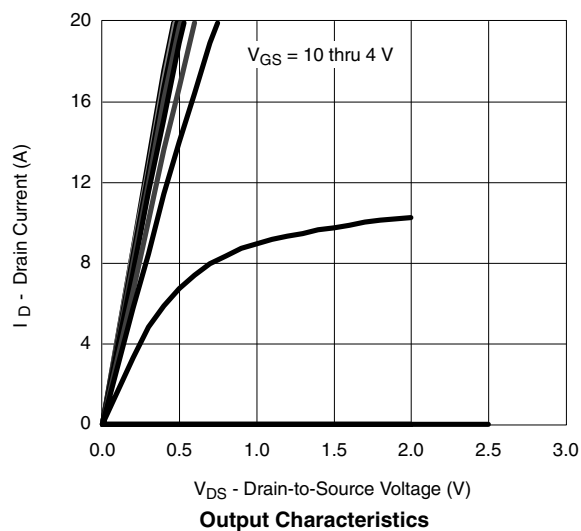
*The power dissipation P_D is based on $T_{J(max)} = 150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

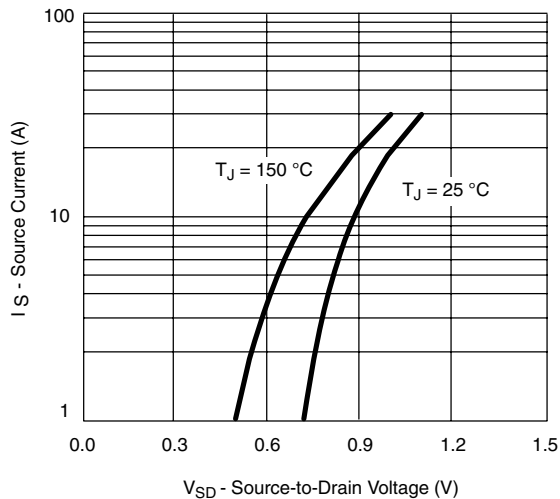
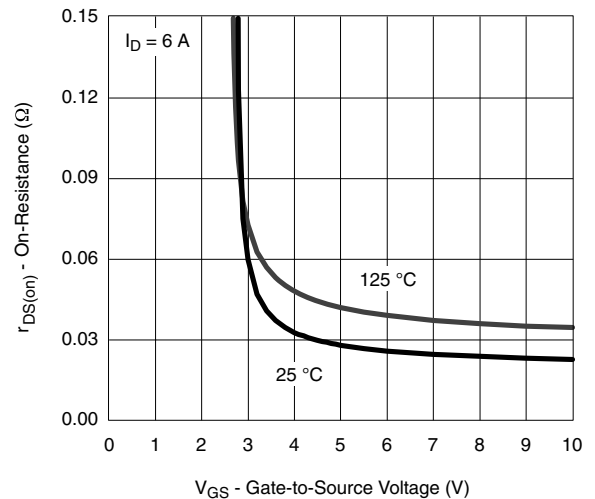
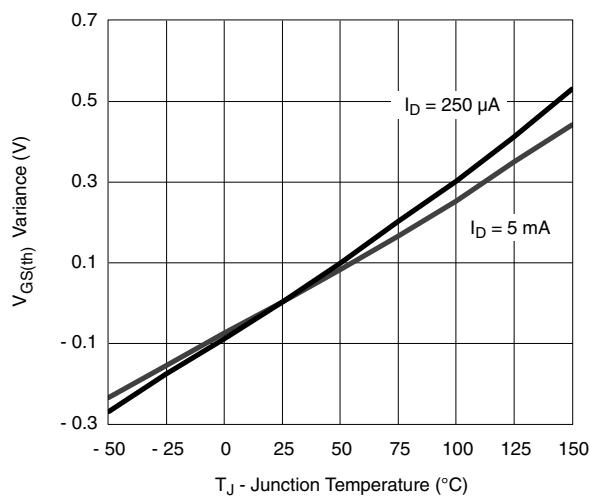
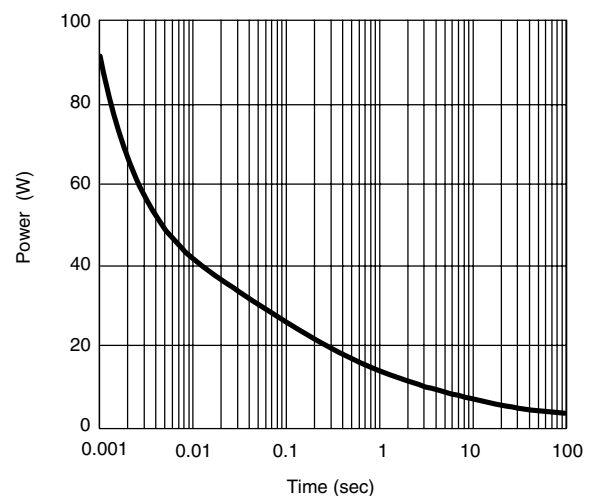
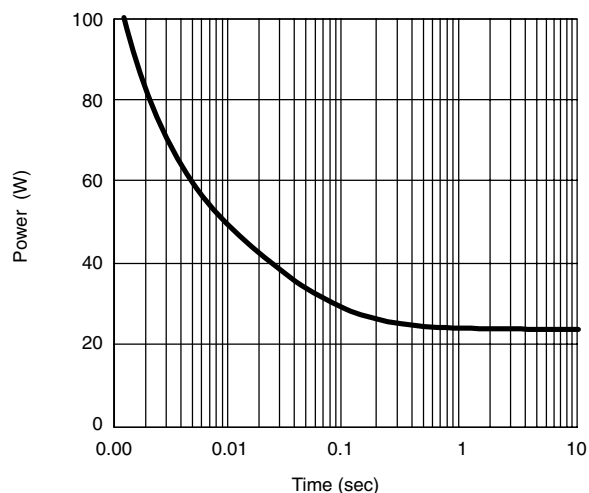
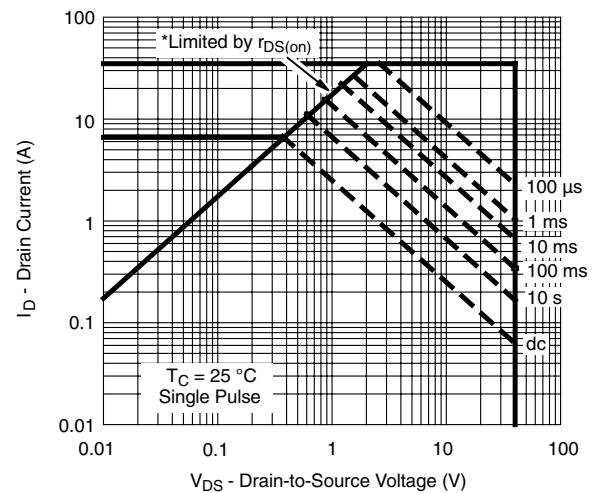
N-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless noted


Normalized Thermal Transient Impedance, Junction-to-Ambient

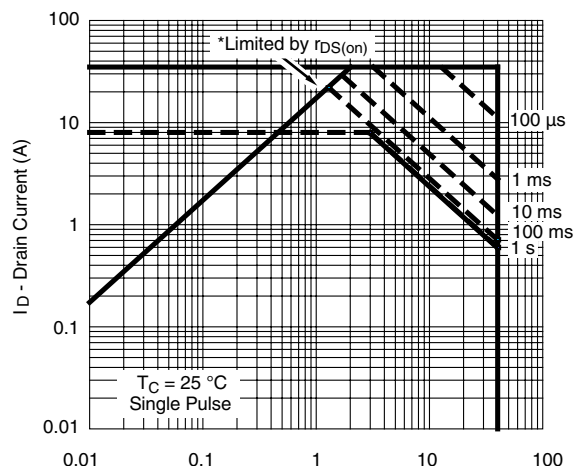


Normalized Thermal Transient Impedance, Junction-to-Case

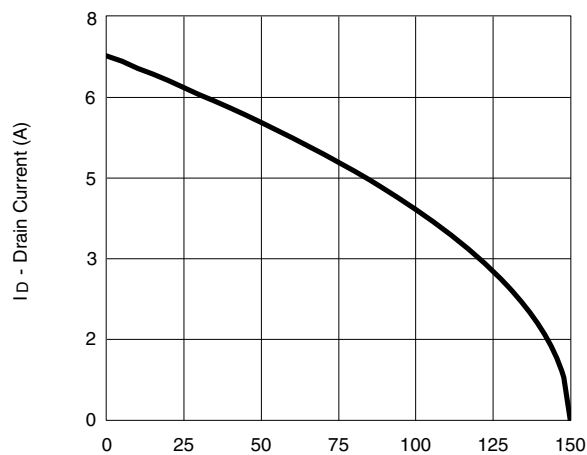
P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless noted

P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless noted

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage

Single Pulse Power, Junction-to-Ambient

Single Pulse Power, Junction-to-Case

Safe Operating Area, Junction-to-Ambient

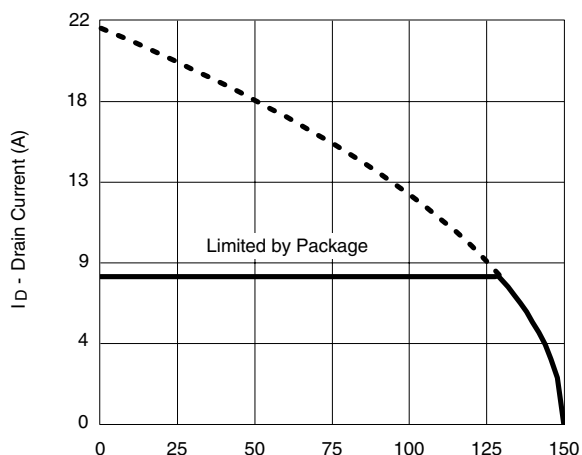
P-CHANNEL TYPICAL CHARACTERISTICS 25 °C, unless noted



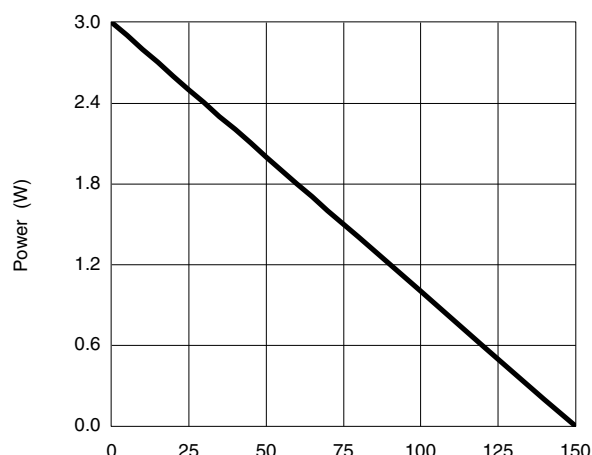
* $V_{GS} >$ minimum V_{GS} at which $r_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Case



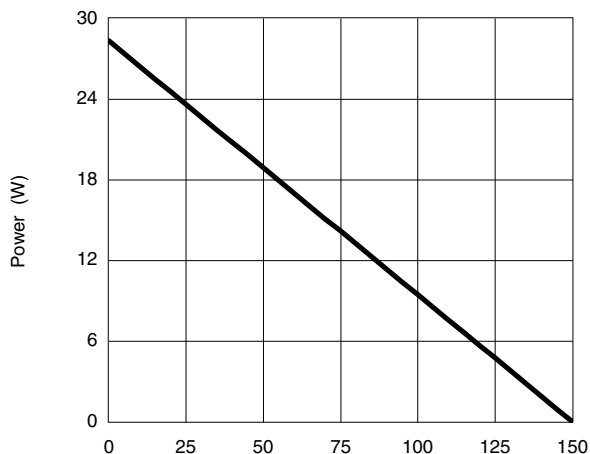
Current Derating, Junction-to-Ambient



Current Derating, Junction-to-Case

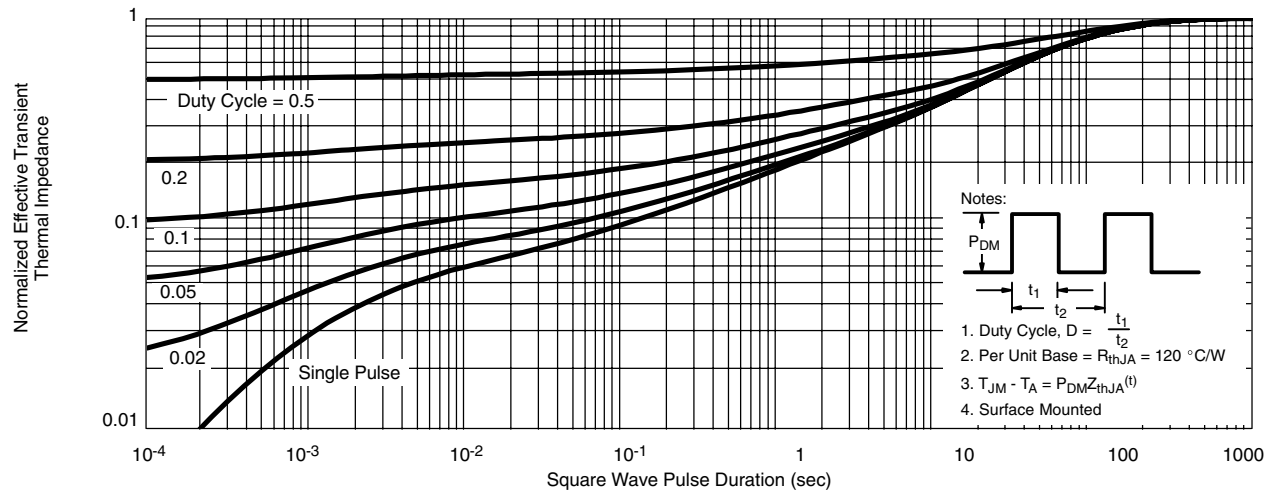
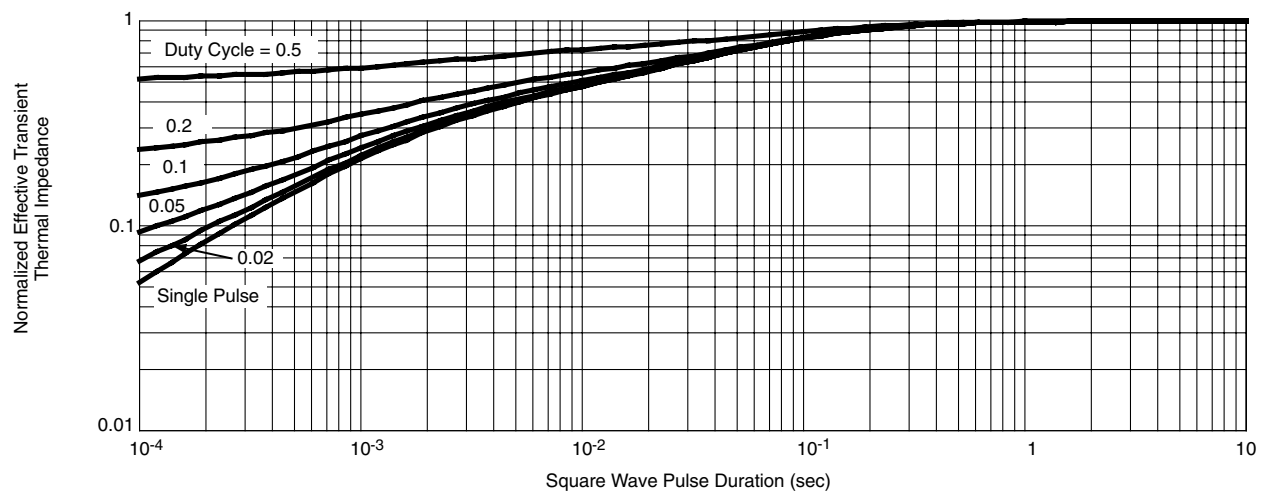


Power Derating, Junction-to-Ambient



Power Derating, Junction-to-Case

*The power dissipation P_D is based on $T_{J(max)} = 150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

**P-CHANNEL TYPICAL CHARACTERISTICS** 25 °C, unless noted**Normalized Thermal Transient Impedance, Junction-to-Ambient****Normalized Thermal Transient Impedance, Junction-to-Case**

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <http://www.vishay.com/ppg?74401>.



Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Данный компонент на территории Российской Федерации

Вы можете приобрести в компании MosChip.

Для оперативного оформления запроса Вам необходимо перейти по данной ссылке:

<http://moschip.ru/get-element>

Вы можете разместить у нас заказ для любого Вашего проекта, будь то серийное производство или разработка единичного прибора.

В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

Офис по работе с юридическими лицами:

105318, г.Москва, ул.Щербаковская д.3, офис 1107, 1118, ДЦ «Щербаковский»

Телефон: +7 495 668-12-70 (многоканальный)

Факс: +7 495 668-12-70 (доб.304)

E-mail: info@moschip.ru

Skype отдела продаж:

moschip.ru

moschip.ru_4

moschip.ru_6

moschip.ru_9